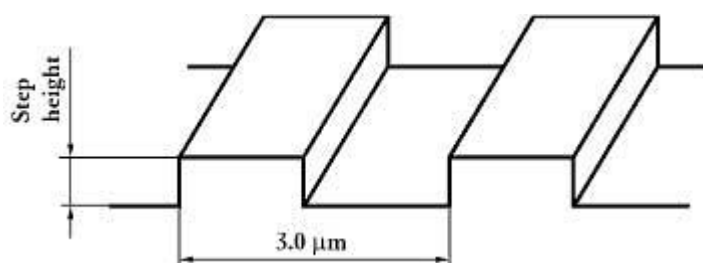
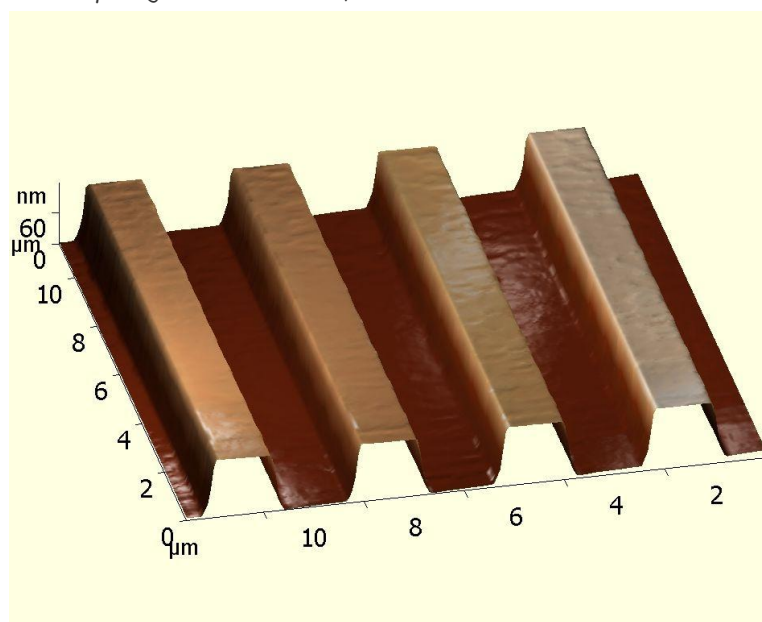


## Product Description

Calibration grating TGZ4 for Z-axis calibration (step height  $1517 \pm 20 \text{ nm}$ ) and nonlinearity measurements.



Step height is the average meaning based on the measurements of 5 gratings with the same height (from the batch of 300 gratings) by AFM calibrated with help of PTB certified grating TGZ1. Basic step height can vary from the specified one within  $\pm 10\%$  depending on the batch (for example TGZ4 grating can have step height  $1600 \pm 20 \text{ nm}$ ).



AFM image of TGZ2 grating (step height  $110 \text{ nm}$ ).

## General Features

Structure	step - $\text{SiO}_2$ , bottom - Si
Pattern type	2-Dimensional
Period	$3 \pm 0,05 \mu\text{m}$
Height	$1517 \pm 20 \text{ nm}^*$
Chip size	$5 \times 5 \times 0,5 \text{ mm}$

Effective area

central square 3x3 mm